Generalizing Nyquist Electronic Noise in the Hydrodynamic Regime

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Electronic noise thermometry is a wellestablished technique to access the temperature of electrons. This technique is rooted in the fluctuation-dissipation relation relating the current fluctuations to the electronic conductivity. The fluctuationdissipation theorem assumes quasi-thermal equilibrium of electrons, a hypothesis which is not met under large bias in graphene where drift velocity \boldsymbol{v}_{F} . [1-3]

I will show that Nyquist formula can be extended to large drift velocity cases in the hydrodynamic electronic transport regime. This regime is naturally met in high-mobility graphene field-effect transistors under large bias because the electron gas self-heating leads to the dominance of electronelectron collisions over competing collision mechanisms. [4] In this regime, the Nyquist formula of noise is corrected by a multiplicative factor which depends on drift velocity and band structure. [5]

References

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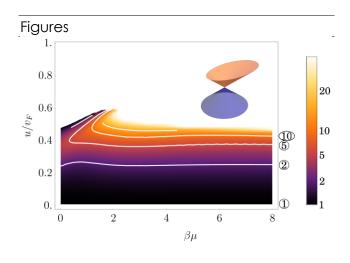


Figure 1: Drift correction factor α to the Nyquist noise formula for monolayer graphene function of the reduced chemical potential $\mu/k_{\rm B}T$ and the reduced drift velocity $u/v_{\rm F}$. At null drift velocity, $\alpha = 1$, and it increases with drift velocity ($\alpha = 2,5,10$ for consecutive white lines). Noise fluctuations diverge when the drift velocity approaches the electronic sound velocity.s